

Search Notes**Application/Control No.**

10/526,686

Examiner

Son T. Nguyen

Applicant(s)/Patent under Reexamination

CHARRIN ET AL.

Art Unit

3643

SEARCHED

Class	Subclass	Date	Examiner
47	41.01 41.11	9/26/2006	STN
	41.12 29.7		
	30 66.3		
	66.4 66.1		
	29.1 73		
220	4.21- 4.24		
428	34.1 34.2		
229	106 107		
	115 116		
	117.05		
206	423		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
IPC foreign search: A01G 7/00,7/02, 7/04,5/00,9/02,13/00,13/02; A47G 7/00,7/02,7/04,7/06,7/07	9/26/2006	STN
consulted primaries Shian Luong, class 206 and Steve Castellano, class 220	9/25/2006	STN
text search, see printouts	9/26/2006	STN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner